

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8741	382/115,100,124,125,126,127,181,190,209,218,224,305,278,286;340/5.52,5.53,5.82,5.83,5.84;902/3.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/23 10:41
L2	17	L1 and(footwear or imprint\$1 or shoeprint\$1 or shoe-print\$1 or footprint\$1 or foot-print\$1 or foot near3 print\$1) near7(identif\$8 or obtain\$3 or determin\$3)same imag\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/23 10:42
L3	18	((((footwear or shoeprint\$1 or shoe-print\$1 or shoe near3 print\$1 or footprint\$1 or foot-print\$1 or foot near3 print\$1)near10(identif\$8 or obtain\$3 or determin\$3 or acquir\$3 or captur\$3 or detect\$4 or sens\$3)same imag\$3) and (co-ordinates or points) same feature\$1) and (compar\$3 or match\$3) same(distance\$1 or spatial))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/23 11:48
L4	4	((footwear or shoeprint\$1 or shoe-print\$1 or shoe near3 print\$1 or footprint\$1 or foot-print\$1 or foot near3 print\$1)near10(identif\$8 or obtain\$3 or determin\$3 or acquir\$3 or captur\$3 or detect\$4 ))same ((co-ordinates or points)near10 feature\$1) and (compar\$3 or match\$3) same(distance\$1 or spatial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/23 11:53
L5	46	((footwear or shoeprint\$1 or shoe-print\$1 or shoe near3 print\$1 or footprint\$1 or foot-print\$1 or foot near3 print\$1)same ((compar\$3 or match\$3) near10(distance\$1 or spatial)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/23 11:56

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